

Fast Cross-
Validation via
Sequential
Analysis

Tammo
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Motivation

Fast CV
Algorithm
Meta-parameters
Example Run

Experiments

Test Error
Speed Increase

Conclusion

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Machine Learning Group
Technische Universität Berlin

16.12.2011 Big Learning Workshop

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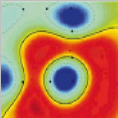
- Cross-validation is an indispensable tool for applied ML but unfortunately very time consuming
- Example *fitted Q iteration*:

$$\overbrace{10 \times 10 \times 10}^{\text{Cross-Validation}} \times \underbrace{50}_{\text{max. iter.}} \times \underbrace{10}_{\text{reps.}} = 500,000 \text{ reg. problems}$$

parameter fold

- Directly optimizing the error landscape to avoid calculations difficult due to noise
- Our approach: use increasing subsets of the training data
 - 1 smaller subsets \rightarrow less training time
 - 2 more training data \rightarrow better error estimate
 - 3 relative behavior of parameter configurations converges

Motivation – Main Idea (Average over 500 Reps.)



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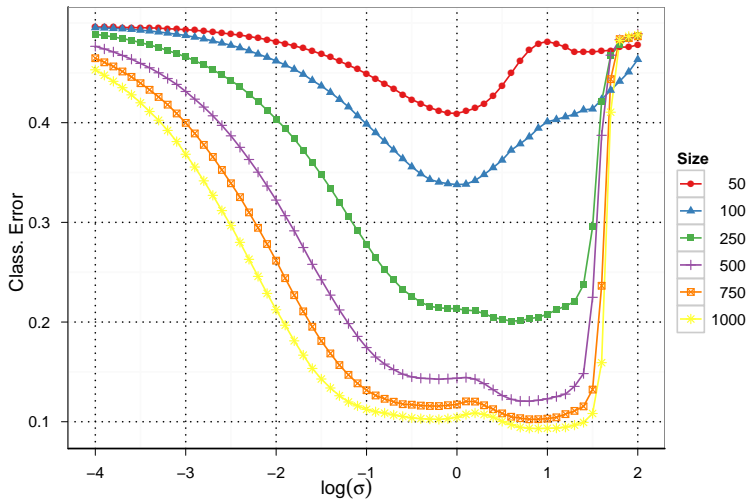
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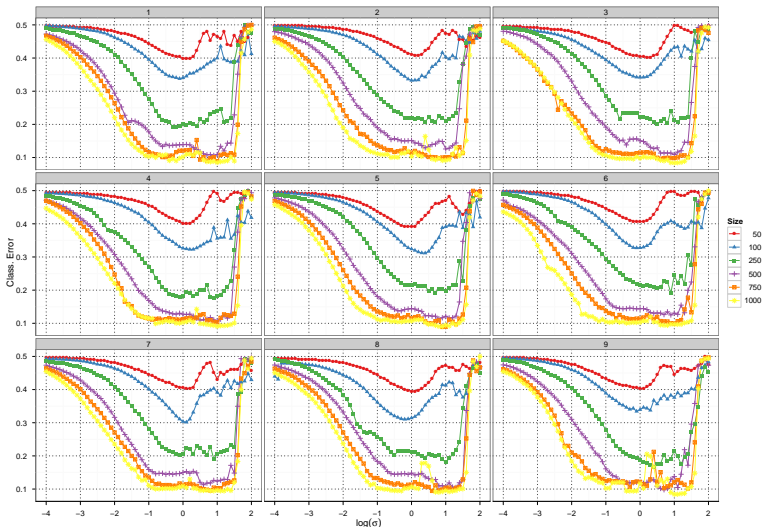
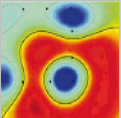
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Motivation – Main Idea (Individual Reps.)



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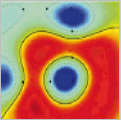
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Motivation – Exploitation

■ Observations:

- ❶ Individual runs are *noisy*, but at least we can see the tendency
- ❷ A lot of *underperforming* parameter configurations
- ❸ We can estimate the correct parameter on a *sufficiently large subset* of the data

■ Exploitation:

- ❶ Transformation of the pointwise test errors of the configurations into a binary *top or flop* scheme
- ❷ Dropping of *significant loser configurations* along the way via tests from the sequential analysis framework
- ❸ *Early stopping* of the procedure, when we have seen enough data for a stable parameter estimation

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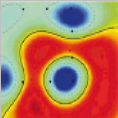
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Fast Cross-Validation Procedure – Algorithm



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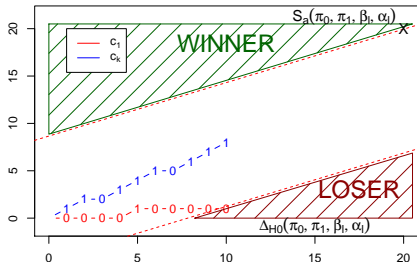
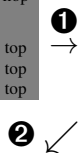
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conf.	data points						
	d_1	d_2	d_3	\dots	d_{n-1}	d_n	
c_1	-2.2	-1.9	-1.8	\dots	2.1	1.5	flop
c_2	-1.9	-2.4	-2.3	\dots	1.9	2.4	flop
c_3	-1.4	-0.9	-0.7	\dots	0.5	0.5	flop
\vdots	\vdots	\vdots	\vdots	\vdots	\vdots	\vdots	\vdots
c_{k-2}	0.6	0.6	0.7	\dots	-0.8	-0.4	top
c_{k-1}	0.1	0.5	0.7	\dots	-0.9	-0.1	top
c_k	0.5	0.4	0.6	\dots	-0.3	0.0	top

pointwisePerformance matrix

										steps	
										1	2
0	0	0	0	0	1	0	0	0	0	0	0
0	1	0	0	0	0	0	0	0	0	0	0
0	1	1	0	0	1	0	0	0	0	0	0
										\vdots	
0	1	0	1	1	1	1	0	1	1	1	1
0	1	1	1	1	1	1	0	1	1	1	1
1	1	0	1	1	1	1	0	1	1	1	1

trace matrix



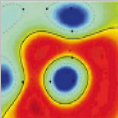
	7	8	9	10
c_3	0	0	0	0
\vdots	\vdots	\vdots	\vdots	\vdots
c_{k-2}	1	0	1	1
c_{k-1}	0	1	1	1
c_k	0	1	1	1

$$\Delta = N/20$$

$$\text{modelSize} = 10\Delta$$

$$n = N - 10\Delta$$

Meta-parameters – Selection of Test Parameters



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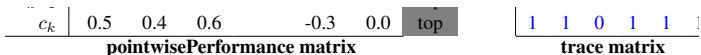
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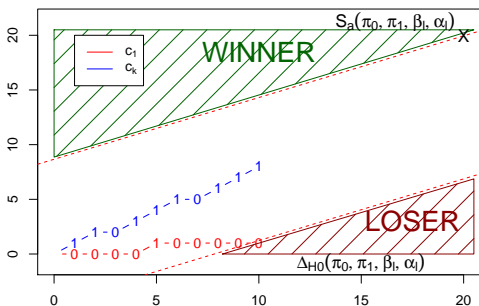
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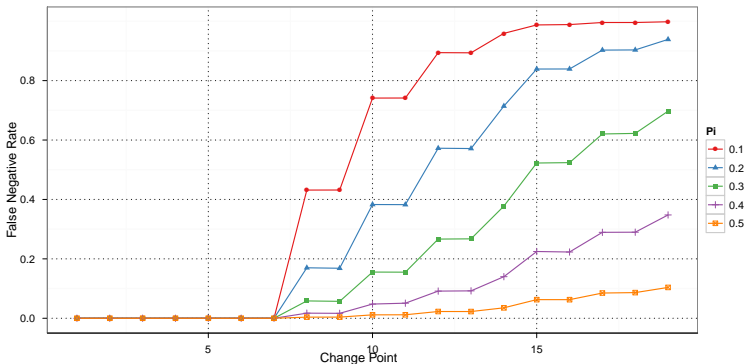
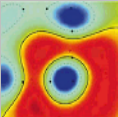


—
—
 c
 c_k
 c_k
 c
mod

$$(\pi_0, \pi_1) = \operatorname{argmax}_{\pi'_0, \pi'_1} \Delta_{H_0}(\pi'_0, \pi'_1, \beta_l, \alpha_l)$$

$$\text{s.t. } S_a(\pi'_0, \pi'_1, \beta_l, \alpha_l) \in (\text{steps} - 1, \text{steps}]$$

Meta-parameters – False Negative Rate



$$0 \leq \frac{cp}{\text{steps}} \leq \underbrace{\frac{\log \frac{\beta_I}{1-\alpha_I} \log \frac{\pi_1}{\pi_0}}{\log \frac{1-\beta_I}{\alpha_I} \log \frac{1-\pi_1}{1-\pi_0}}}_{\text{security zone (false negative rate of 0)}} \quad \text{with steps} \geq \left\lceil \log \frac{1-\beta_I}{\alpha_I} / \log 2 \right\rceil$$

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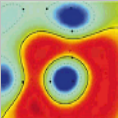
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Fast Cross-Validation Procedure – Example Run



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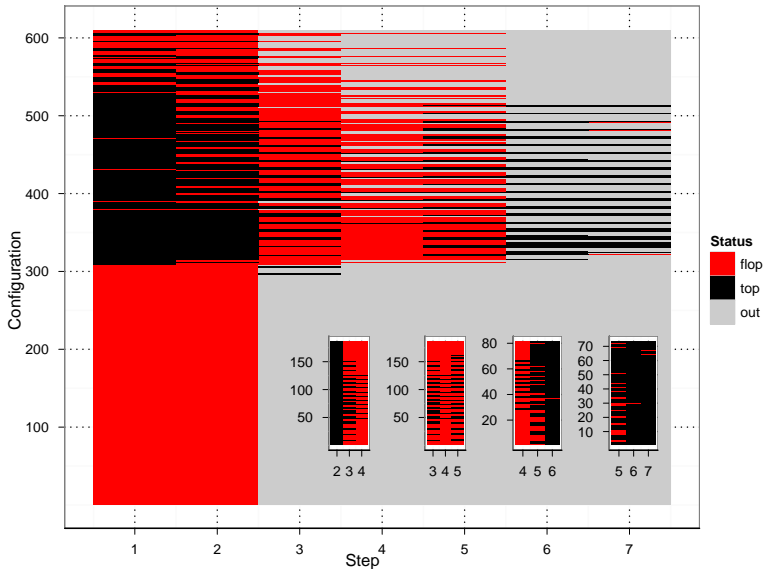
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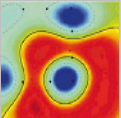
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Experimental Setup

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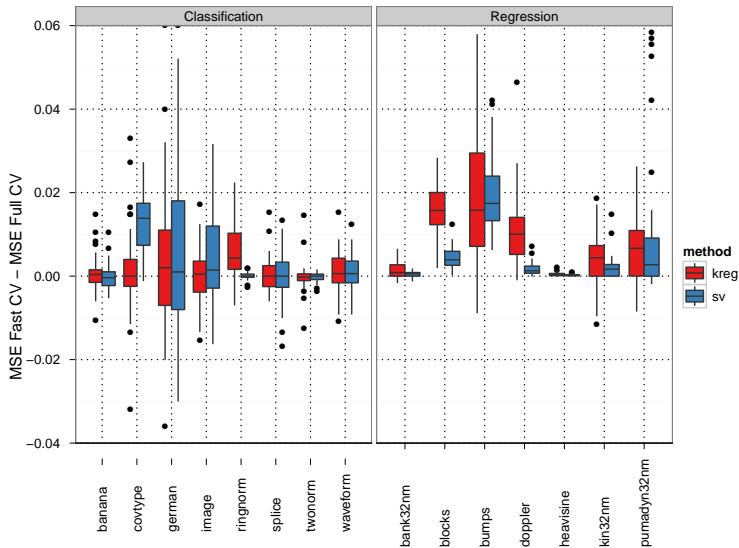
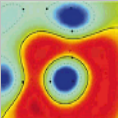
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- 8 classification and 7 regression data sets
- For each dataset:
 - $\frac{1}{2}$ for parameter estimation, $\frac{1}{2}$ for test error estimation
 - SVM/SVR and Kernel Ridge Regression/Kernel Logistic Regression with Gaussian kernel using 610 parameter configurations
 - Parameter estimation with:
 - Full 10-fold cross-validation
 - Fast cross-validation procedure with 10 steps
- Repeated 50 times with different splits for each dataset
- Compare:
 - Test error difference of fast versus full cross-validation
 - Relative speed factor, i.e. $\frac{\text{time full cross-validation}}{\text{time fast cross-validation}}$

Experiments – Test Error



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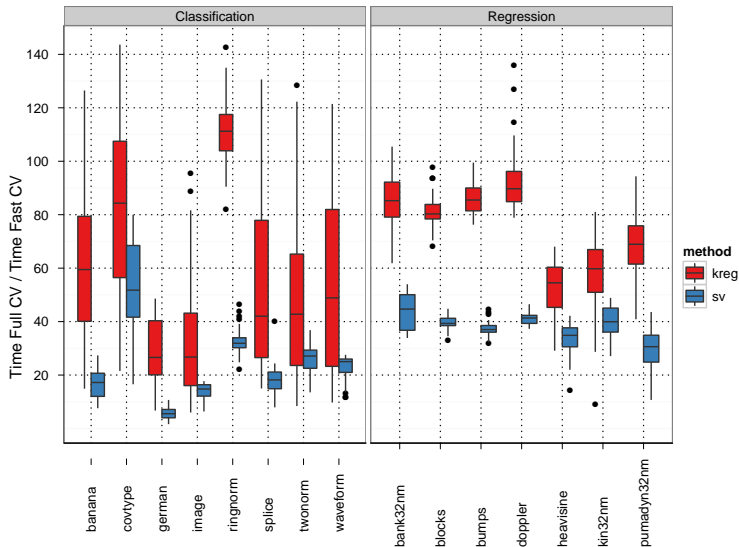
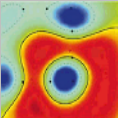
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Experiments – Speed Increase



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Fast Cross-Validation Procedure – Summary

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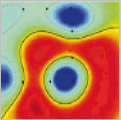
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- Motivation: we can estimate the correct parameter on a *sufficiently large subset* of the data
- Transformation: *Race of configurations* evaluated on linearly increasing subsets of the data
- At each step of this race:
 - 1 Transform the test errors on individual data points of the remaining configurations into a binary *top or flop* scheme
 - 2 Drop significant loser configurations along the way using tests from the sequential analysis framework
 - 3 Apply distribution free testing techniques to decide, whether we have gathered enough evidence for a stable parameter estimation



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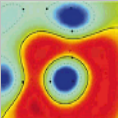
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Questions? Remarks?
Thanks for your attention!

Experiments – Traces Classification



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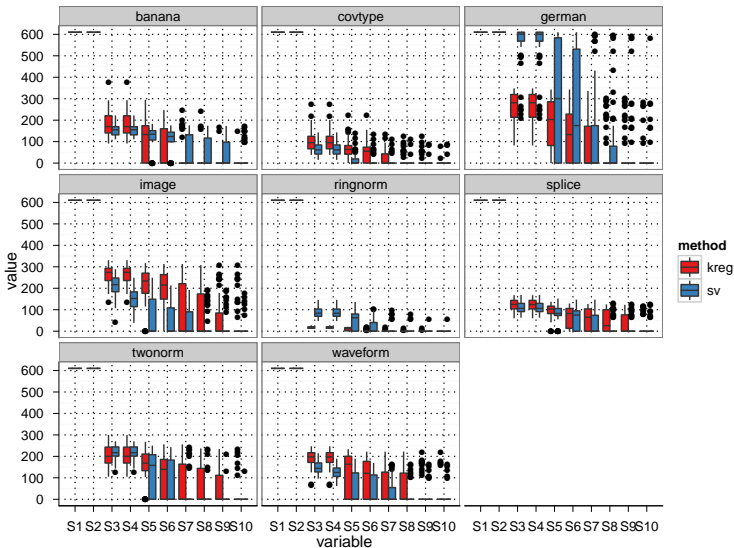
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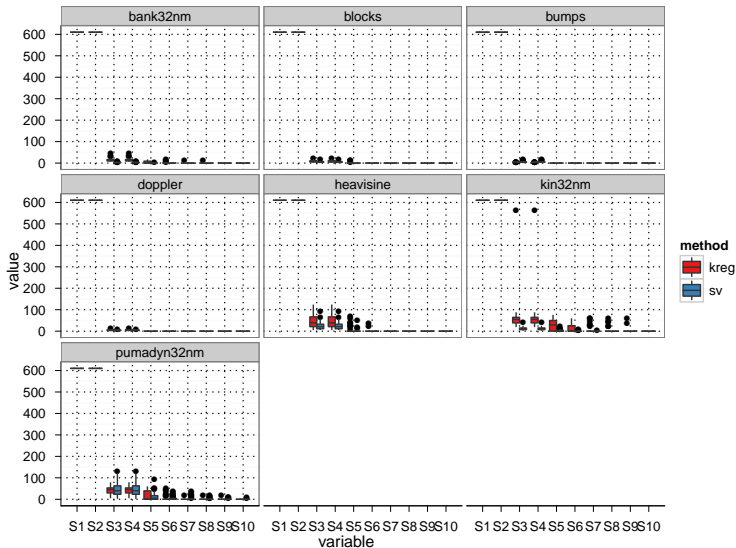
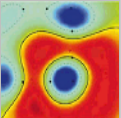
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Experiments – Traces Regression



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